Notice of Allowability	Application No.	Applicant(s)		
	10/603,461	HENSON, TIMOTHY		
	Examiner	Art Unit		
	Matthew Landau	2815		
The MAILING DATE of this communication appearable All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIOF the Office or upon petition by the applicant. See 37 CFR 1.313	(OR REMAINS) CLOSED in this ap or other appropriate communicatio GHTS. This application is subject and MPEP 1308.	oplication. If not include in will be mailed in due	ed course. THIS	
1. A This communication is responsive to the amendment filed in	<u>November 17, 2004</u> .			
2. X The allowed claim(s) is/are <u>1,4-10 and 12-20</u> .				
3. A The drawings filed on 17 November 2004 are accepted by	the Examiner.			
 4. Acknowledgment is made of a claim for foreign priority una) All b) Some* c) None of the: 1. Certified copies of the priority documents have 2. Certified copies of the priority documents have 3. Copies of the certified copies of the priority documents have International Bureau (PCT Rule 17.2(a)). 	been received. been received in Application No		tion from the	
* Certified copies not received:				
Applicant has THREE MONTHS FROM THE "MAILING DATE" noted below. Failure to timely comply will result in ABANDONM THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.		complying with the rec	quirements	
5. A SUBSTITUTE OATH OR DECLARATION must be submi INFORMAL PATENT APPLICATION (PTO-152) which give	itted. Note the attached EXAMINEF es reason(s) why the oath or declar	R'S AMENDMENT or N ation is deficient.	OTICE OF	
 CORRECTED DRAWINGS (as "replacement sheets") mus (a) including changes required by the Notice of Draftspers 1) hereto or 2) to Paper No./Mail Date (b) including changes required by the attached Examiner's Paper No./Mail Date Identifying indicla such as the application number (see 37 CFR 1. each sheet. Replacement sheet(s) should be labeled as such in the 	on's Patent Drawing Review (PTO Amendment / Comment or in the . 84(c)) should be written on the drawi	Office action of ings in the front (not the	back) of	
DEPOSIT OF and/or INFORMATION about the deposit attached Examiner's comment regarding REQUIREMENT I	sit of BIOLOGICAL MATERIAL	must be submitted. N	Note the	
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Attachment(s) 1. ☐ Notice of References Cited (PTO-892)	5. Notice of Informal F	Patent Application (PTC	7 ₌152\	
2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948)	6. Interview Summary	ew Summary (PTO-413),		
 Information Disclosure Statements (PTO-1449 or PTO/SB/0 Paper No./Mail Date 		o./Mail Date 's Amendment/Comment		
4. ☐ Examiner's Comment Regarding Requirement for Deposit	8. 🛛 Examiner's Statem	ent of Reasons for Allo	wance	
of Biological Material	9. Other			
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	superviso	OM THOMAS RY PATENT EXAMINED		

Application/Control Number: 10/603,461

Art Unit: 2815

EXAMINER'S AMENDMENT

An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

Authorization for this examiner's amendment was given in a telephone interview with Kourosh Salehi (Reg. #43,898) on February 11, 2005.

Please amend the claim(s) as follows:

10. (Currently Amended) A MOSgated semiconductor device comprising:

a semiconductor die having an epitaxial layer of a first conductivity type formed over a substrate;

a channel region of a second conductivity type formed in said epitaxial layer;

a plurality of spaced trenches formed in said epitaxial layer;

a first region of a first conductivity type formed at the bottom of each trench, each said first region of said first conductivity type being adjacent to said epitaxial layer and of a higher conductivity than said epitaxial layer;

a plurality of source regions of said first conductivity type each disposed adjacent a trench;

a source contact formed over said epitaxial layer and in ohmic contact with said plurality of source regions; wherein a conductivity of said first regions of said first conductivity type and a

conductivity of said field relief regions are substantially equal [[being selected to create a superjunction in said device]].

Allowable Subject Matter

Claims 1, 4-10, and 12-20 are allowed.

The following is an examiner's statement of reasons for allowance:

Regarding claim 1, the prior art of record, either singularly or in combination, does not disclose or suggest the combination of limitations including wherein said field relief regions are spaced from said channel region.

Regarding claim 10, the prior art of record, either singularly or in combination, does not disclose or suggest the combination of limitations including wherein a conductivity of said first regions of said first conductivity type and a conductivity of said field relief regions are substantially equal.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Matthew C. Landau whose telephone number is (571) 272-1731. Application/Control Number: 10/603,461

Art Unit: 2815

The examiner can normally be reached from 8:30 AM - 5:30 PM. If attempts to reach the

examiner by telephone are unsuccessful, the examiner's supervisor, Tom Thomas can be reached

on (571) 272-1664. The fax phone numbers for the organization where this application or

proceeding is assigned are (703) 872-9306 for regular communications and (703) 872-9306 for

After Final communications.

Any inquiry of a general nature or relating to the status of this application or proceeding

should be directed to the receptionist whose telephone number is (703) 308-0956.

Matthew C. Landau

Examiner

Page 4

TOM THOMAS

SUPERVISORY PATENT EXAMINER

February 11, 2005